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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
09/450,351	11/29/1999	ТОМОЕ УАМАМОТО	SHM-00901	7516	
26339 75	590 11/05/2002				
PATENT GR	OUP	EXAMINER			
CHOATE, HALL & STEWART EXCHANGE PLACE, 53 STATE STREET			TSAI, H JEY		
BOSTON, MA 02109			ART UNIT	PAPER NUMBER	
			2812		
			DATE MAILED: 11/05/2002	DATE MAILED: 11/05/2002	

Please find below and/or attached an Office communication concerning this application or proceeding.

	Appl	ication No.	Applicant(s)	Qfn.		
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Office Action Summ		50,351	Art Unit	T		
	·		2812			
The MAILING DATE of this c		y Tsai n the cover sheet w		ddress		
Period for Reply			•			
A SHORTENED STATUTORY PEI THE MAILING DATE OF THIS CO  - Extensions of time may be available under the after SIX (6) MONTHS from the mailing date of - If the period for reply specified above is less th - If NO period for reply is specified above, the m - Failure to reply within the set or extended perio - Any reply received by the Office later than three earned patent term adjustment. See 37 CFR 1  Status	MMUNICATION. provisions of 37 CFR 1.136(a). In this communication. an thirty (30) days, a reply within th aximum statutory period will apply d for reply will, by statute, cause the months after the mailing date of t	no event, however, may a ne statutory minimum of th and will expire SIX (6) MO ne application to become A	reply be timely filed irty (30) days will be considered time NTHS from the mailing date of this of BANDONED (35 U.S.C. § 133).	aly. communication.		
1)⊠ Responsive to communicati	on(s) filed on 27 August	2002 .				
2a)☐ This action is FINAL.	2b)⊠ This action	on is non-final.				
3) Since this application is in c				he merits is		
closed in accordance with the Disposition of Claims	ne practice under <i>Ex par</i>	te Quayle, 1935 C	.D. 11, 455 O.G. 215.			
4)⊠ Claim(s) <u>1-11 and 13-36</u> is/a	are pending in the applic	ation.				
4a) Of the above claim(s)	is/are withdrawn fror	n consideration.				
5) Claim(s) is/are allowe	d.		·			
6)⊠ Claim(s) <u>1-11 and 13-36</u> is/a	re rejected.					
7) Claim(s) is/are object	ed to.					
8) Claim(s) are subject to Application Papers	o restriction and/or elect	ion requirement.				
9) The specification is objected t	to by the Examiner.					
10)☐ The drawing(s) filed on	_is/are: a)☐ accepted or	b)☐ objected to by	the Examiner.			
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).						
11)☐ The proposed drawing correction filed on is: a)☐ approved b)☐ disapproved by the Examiner.						
If approved, corrected drawing						
12) The oath or declaration is obj	ected to by the Examine	r.				
Priority under 35 U.S.C. §§ 119 and	120					
13) ☐ Acknowledgment is made of	a claim for foreign priori	ty under 35 U.S.C	. § 119(a)-(d) or (f).			
a) ☐ All b) ☐ Some * c) ☐ No	one of:					
	priority documents have					
2. Certified copies of the	priority documents have	been received in	Application No			
	e International Bureau (I	PCT Rule 17.2(a))		l Stage		
14)☐ Acknowledgment is made of a	claim for domestic prior	ity under 35 U.S.C	. § 119(e) (to a provisiona	al application).		
a) ☐ The translation of the foreign language provisional application has been received.  15)☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. §§ 120 and/or 121.						
Attachment(s)						
Notice of References Cited (PTO-892)     Notice of Draftsperson's Patent Drawing II     Information Disclosure Statement(s) (PTO			v Summary (PTO-413) Paper N f Informal Patent Application (P <sup>o</sup>			
U.S. Patent and Trademark Office PTO-326 (Rev. 04-01)	Office Action Su	ımmary	Part o	of Paper No. 28		

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## Claim Rejections - 35 U.S.C. § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 1-11 and 13-36 are rejected under 35 U.S.C. 103(a) as being unpatentable over DeBoer et al. 6,146,959 or Huang 6,057,189, in view of Tamaru et al. 6,103,566, or Nishikawa 6,087,261 or Lee et al. 6,010,940, all are previously applied.

The reference(s) teach the features:

DeBoer et al. substantially discloses a method of forming a capacitor on the semiconductor device, which includes :

forming a tantalum oxide dielectric layer 38, fig. 2+, annealing the substrate and forming a CVD TiN directly on the layer 38, see col. 4, lines 31+, or

treating substrate in the chamber with at least one of a gas containing non-reactive NF3 or hydrazine gas and  $NH_3$  to form a layer 40, col. 4, lines 29+,

annealing substrate, and forming a CVD TiN film 42 directly on dielectric layer 38.

Huang substantially discloses a method of forming a capacitor on the semiconductor device, which includes:

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forming a tantalum oxide dielectric layer 36, fig. 2C+, treating substrate with non-reactive nitrogen gas , col. 4, lines 47+,

forming a CVD TiN film 38 over dielectric layer 38.

Tamaru et al. substantially discloses a method of forming a capacitor on the semiconductor device, which includes:

forming a tantalum oxide dielectric layer 5, fig. 4B, and col. 16, lines 7+,

treating substrate in the chamber with at least one of a gas containing non-reactive helium or Ar or  $N_2$  gas and  $NH_3$ , heating the substrate in the  $NH_3$  col. 9, lines 44+. forming a TiN film over the dielectric layer 5.

Nishikawa substantially discloses a method of forming a capacitor on the semiconductor device, which includes:

forming a tantalum oxide dielectric layer 5, fig. 4B, treating substrate in the chamber with at least one of a gas containing non-reactive  $NH_3$  and helium gases flow, col. 9, lines 1+,

heating the substrate in the  $\mathrm{NH}_3$  ambient at about 0.15 torr, fig. 6, col. 9, lines 30+,

forming a TiN film over the dielectric layer 5.

Since, Tamaru, Nishikawa and Lee et al. teach details of forming a CVD TiN. It would have been obvious to one having

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ordinary skill in the art at the time the invention was made to have using Tamaru, Nishikawa and Lee et al.'s CVD TiN process to form a TiN film over dielectric layer

Applicant's arguments filed July 12, 2002, 2002 have been fully considered but they are not persuasive. Because DeBoer clearly teaches in col.4, lines 31+, that forming dielectric layer 38, then annealing and forming TiN directly on the layer 39 or forming a dielectric layer 40 on layer 38 then annealing and forming a TiN directly on layer 40. And, Sandhu and Huang clearly teach heating the dielectric layer with non-reactive gas as set forth above.

Any inquiry of a general nature or clerical matters or relating to the status of this application or proceeding should be directed to the Group customer service whose telephone number is (703) 306-3329 and Fax number (703) 306-5515. Group receptionist telephone number 703-308-0956.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to H. Jey Tsai whose telephone number is (703) 308-1374. The examiner can normally be reached on from 7:00 Am to 4:00 Pm., Monday thru Friday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John Niebling can be reached on (703) 308-3325. The fax phone number for this Group is (703) 308-7722.

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H. Je√ Tsai

Primary Examiner

Patent Examining Group 2800

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